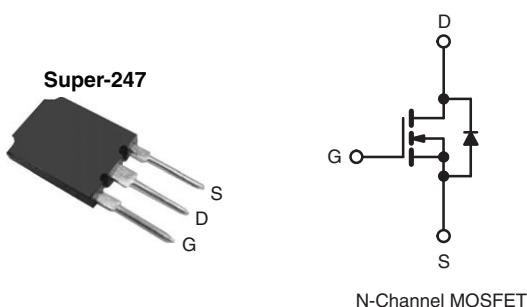


N-Channel 500V(D-S) Super Junction Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	500
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.080
Q _g (Max.) (nC)	350
Q _{gs} (nC)	85
Q _{gd} (nC)	180
Configuration	Single

FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Low R_{DS(on)}
- Compliant to RoHS Directive 2002/95/EC



N-Channel MOSFET

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)				
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	500	V
Gate-Source Voltage		V _{GS}	± 30	
Continuous Drain Current		I _D	40	A
			25	
Pulsed Drain Current ^a		I _{DM}	180	
Linear Derating Factor			4.3	W/°C
Single Pulse Avalanche Energy ^b		E _{AS}	910	mJ
Repetitive Avalanche Current ^a		I _{AR}	40	A
Repetitive Avalanche Energy ^a		E _{AR}	51	mJ
Maximum Power Dissipation	T _C = 25 °C	P _D	530	W
Peak Diode Recovery dV/dt ^c		dV/dt	9.0	V/ns
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Starting T_J = 25 °C, L = 0.82 mH, R_g = 25 Ω, I_{AS} = 47 A (see fig. 12c).
- I_{SD} ≤ 47 A, dI/dt ≤ 230 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.
- 1.6 mm from case.

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	40	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.24	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.23	

SPECIFICATIONS ($T_J = 25 \text{ }^{\circ}\text{C}$, unless otherwise noted)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$	$I_D = 250 \mu\text{A}$	500	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$, $I_D = 1 \text{ mA}$		-	0.60	-	$\text{V}/^{\circ}\text{C}$
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		3.0	-	5.0	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 30 \text{ V}$		-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 500 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	50	μA
		$V_{DS} = 400 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125 \text{ }^{\circ}\text{C}$		-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 28 \text{ A}^b$	-	0.080	-	Ω
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 28 \text{ A}$		23	-	-	S
Dynamic							
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	8310	-	pF
Output Capacitance	C_{oss}			-	960	-	
Reverse Transfer Capacitance	C_{rss}			-	120	-	
Output Capacitance	C_{oss}	$V_{GS} = 0 \text{ V}$	$V_{DS} = 1.0 \text{ V}$, $f = 1.0 \text{ MHz}$	-	10170	-	nC
			$V_{DS} = 400 \text{ V}$, $f = 1.0 \text{ MHz}$	-	240	-	
Effective Output Capacitance	$C_{oss eff.}$		$V_{DS} = 0 \text{ V}$ to 400 V^c	-	440	-	
Total Gate Charge	Q_g	$I_D = 47 \text{ A}$, $V_{DS} = 400 \text{ V}$, see fig. 6 and 13 ^b	-	-	350	ns	
Gate-Source Charge	Q_{gs}		-	-	85		
Gate-Drain Charge	Q_{gd}		-	-	180		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 250 \text{ V}$, $I_D = 47 \text{ A}$, $R_G = 1.0 \Omega$, see fig. 10 ^b	-	25	-	ns	
Rise Time	t_r		-	140	-		
Turn-Off Delay Time	$t_{d(off)}$		-	55	-		
Fall Time	t_f		-	74	-		

Drain-Source Body Diode Characteristics

Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	47	A
Pulsed Diode Forward Current ^a	I_{SM}			-	-	190	
Body Diode Voltage	V_{SD}	$T_J = 25 \text{ }^{\circ}\text{C}$, $I_S = 47 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	1.5	V
Body Diode Reverse Recovery Time	t_{rr}			-	620	940	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	14	21	μC
Body Diode Recovery Current	I_{RRM}			-	38	-	A
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 400 \mu\text{s}$; duty cycle $\leq 2 \%$.
c. $C_{oss eff.}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .

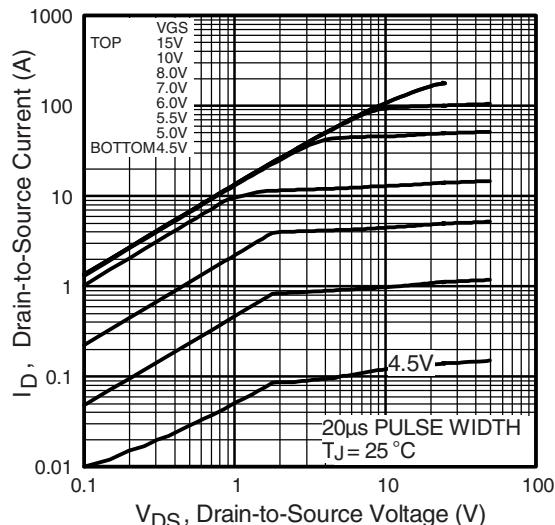
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)


Fig. 1 - Typical Output Characteristics

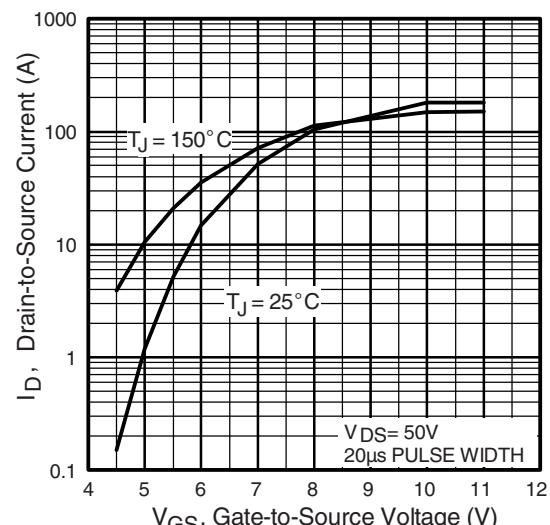


Fig. 3 - Typical Transfer Characteristics

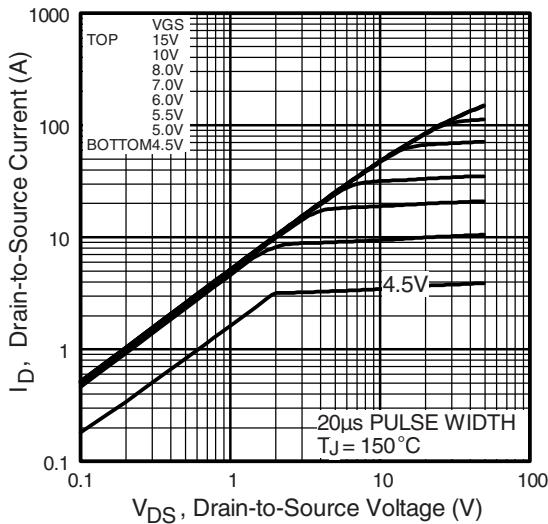


Fig. 2 - Typical Output Characteristics

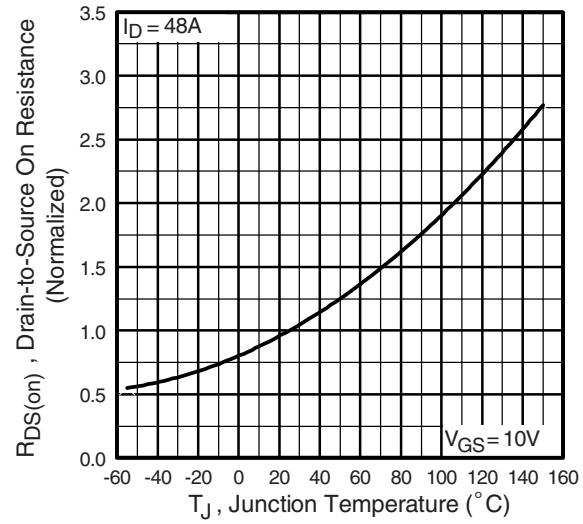
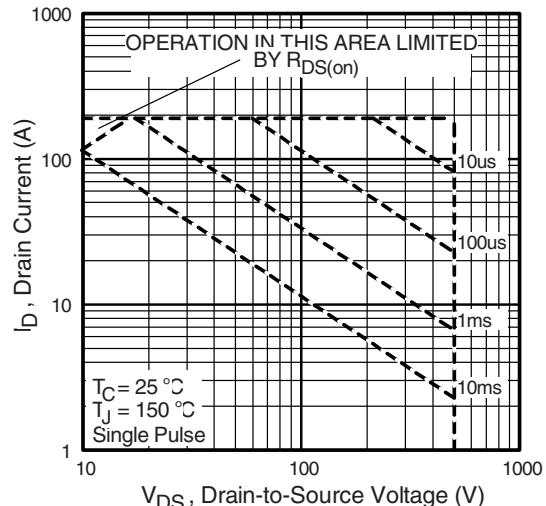
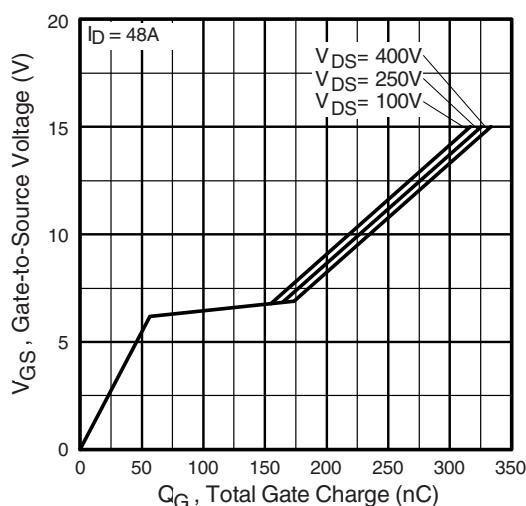
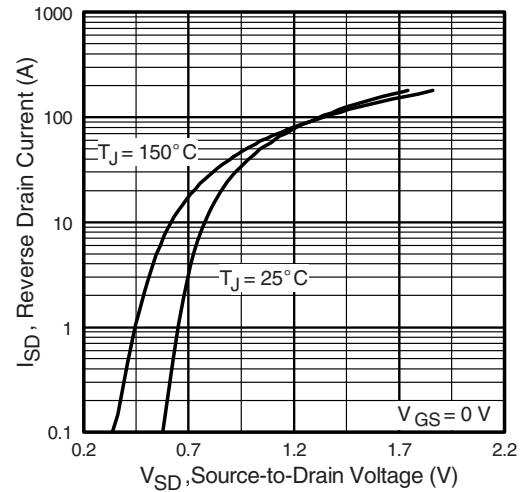
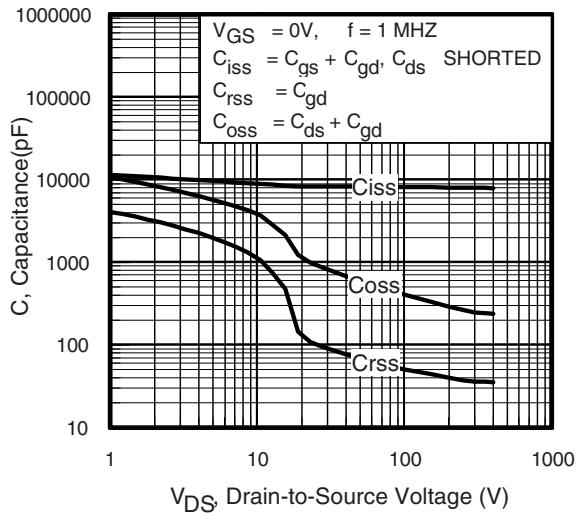


Fig. 4 - Normalized On-Resistance vs. Temperature



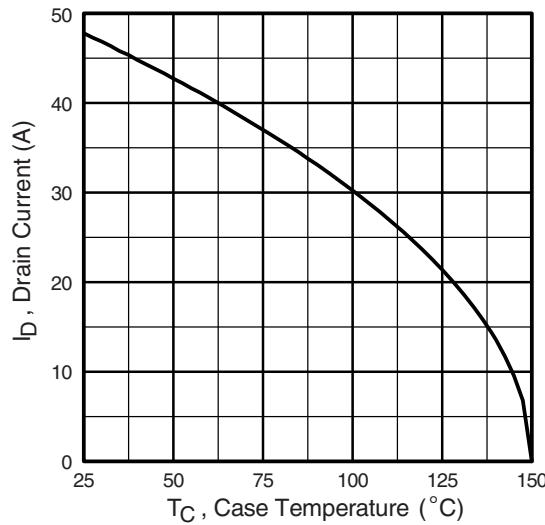


Fig. 9 - Maximum Drain Current vs. Case Temperature

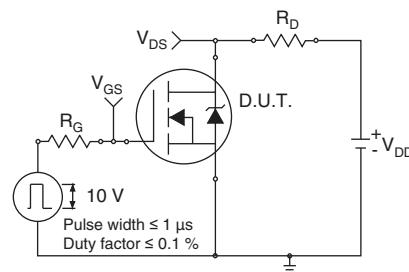


Fig. 10a - Switching Time Test Circuit

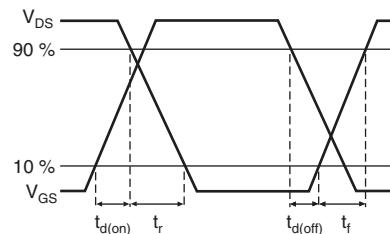


Fig. 10b - Switching Time Waveforms

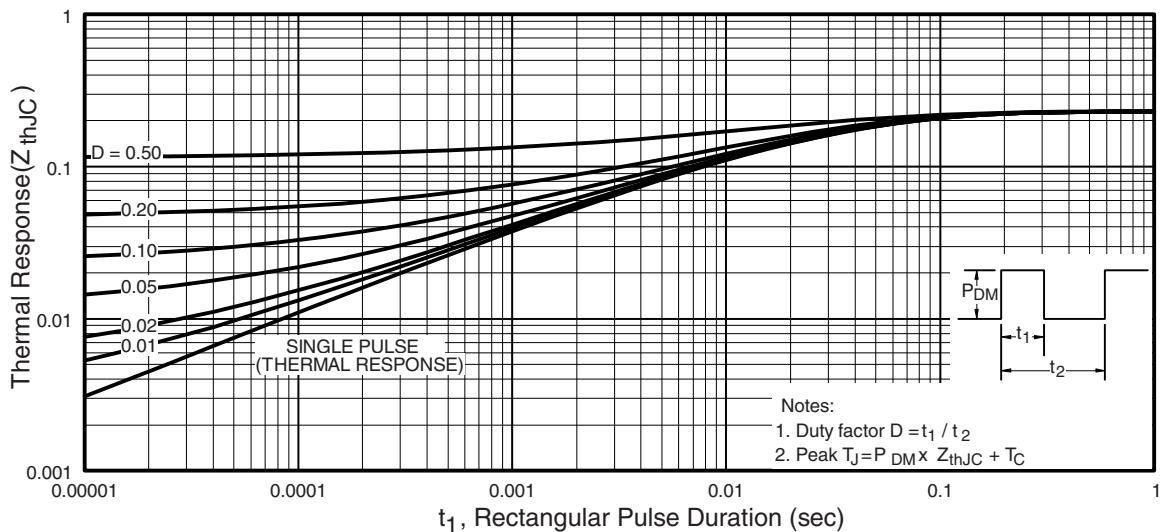


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

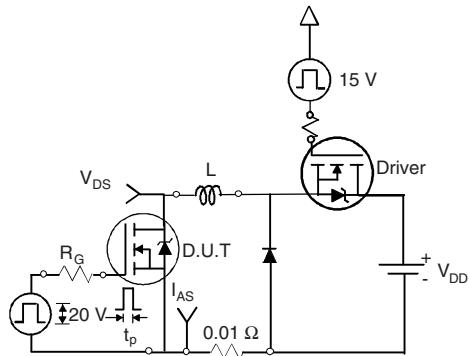


Fig. 12a - Unclamped Inductive Test Circuit

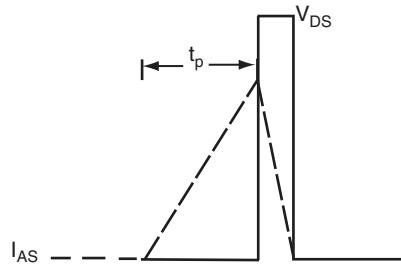


Fig. 12b - Unclamped Inductive Waveforms

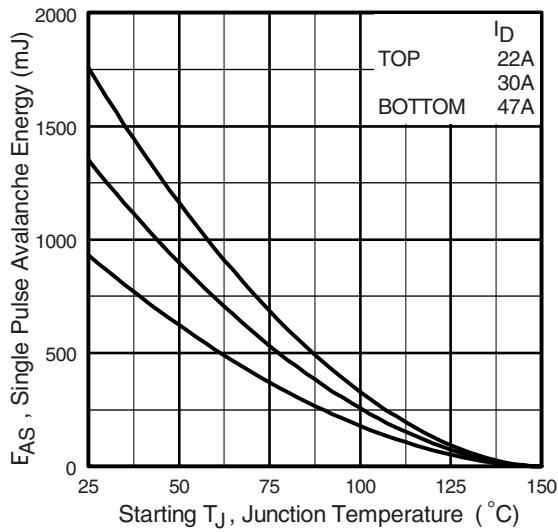


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

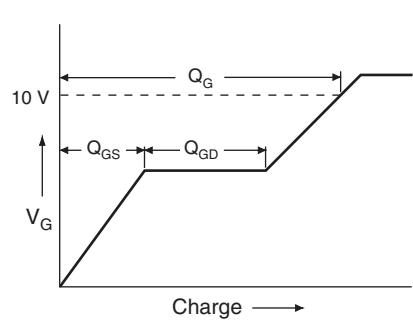


Fig. 13a - Basic Gate Charge Waveform

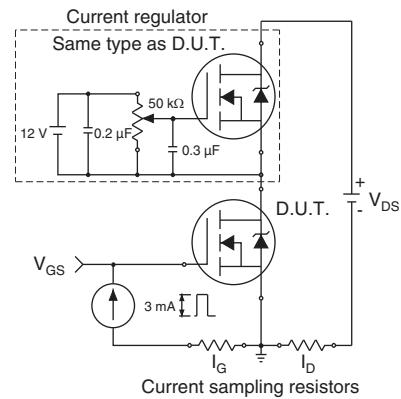
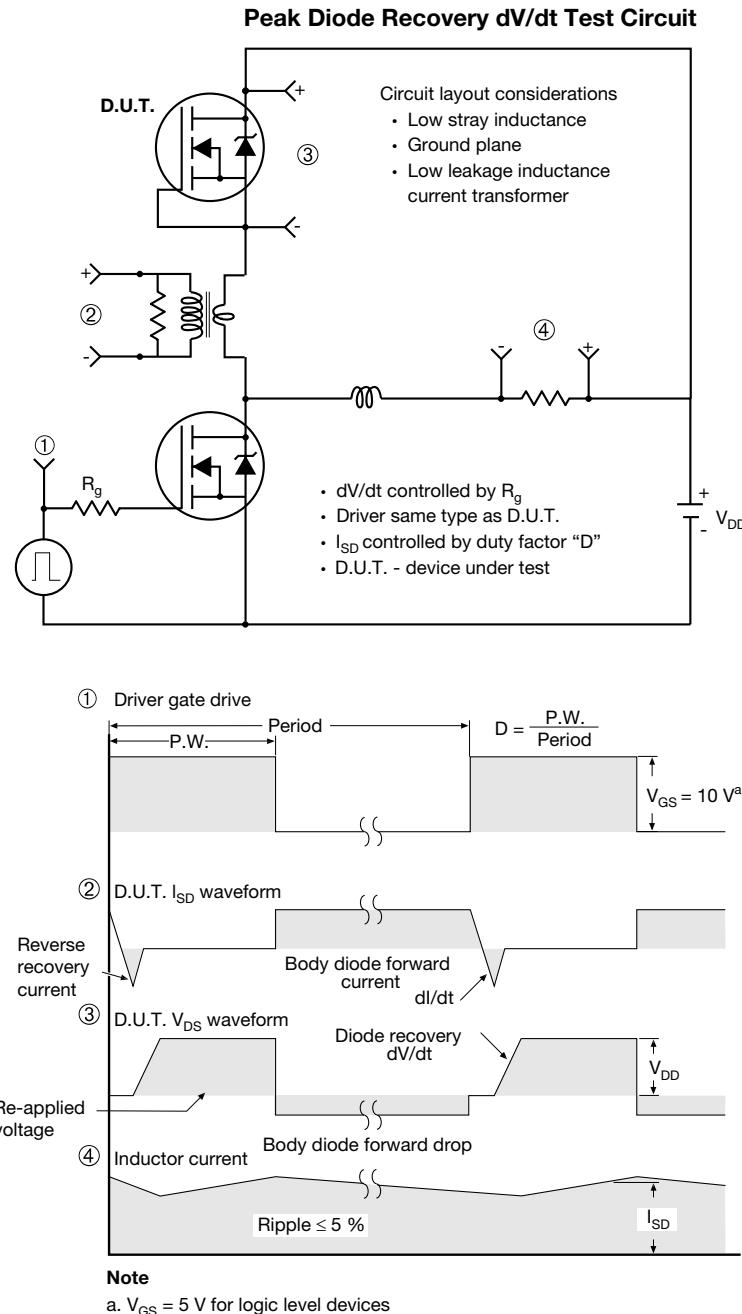
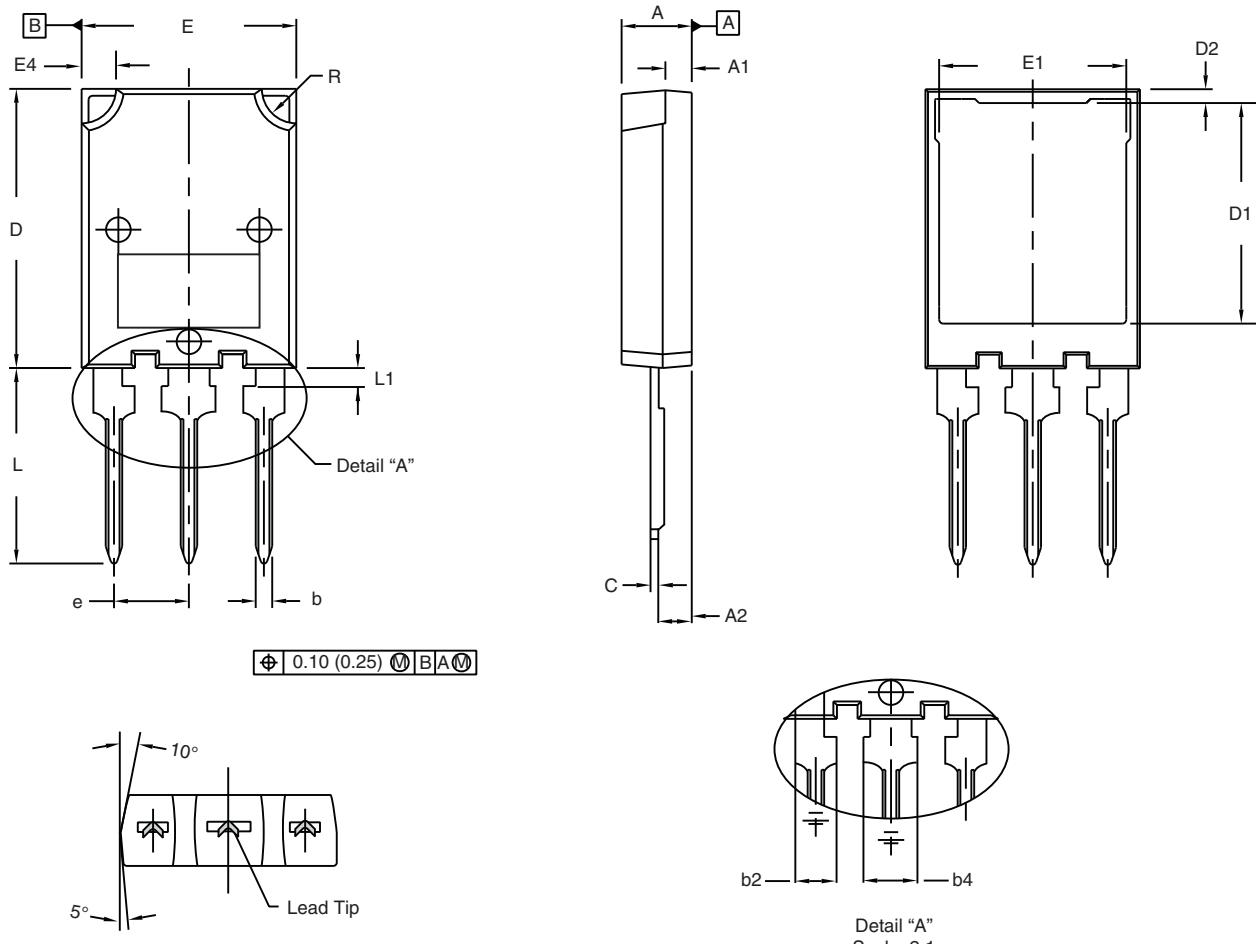


Fig. 13b - Gate Charge Test Circuit

**Fig. 14 - For N-Channel**

TO-274AA (High Voltage)



DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.70	5.30	0.185	0.209
A1	1.50	2.50	0.059	0.098
A2	2.25	2.65	0.089	0.104
b	1.30	1.60	0.051	0.063
b2	1.80	2.20	0.071	0.087
b4	3.00	3.25	0.118	0.128
c (1)	0.38	0.89	0.015	0.035
D	19.80	20.80	0.780	0.819

ECN: X17-0056-Rev. B, 27-Mar-17

DWG: 5975

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
D1	15.50	16.10	0.610	0.634
D2	0.70	1.30	0.028	0.051
E	15.10	16.10	0.594	0.634
E1	13.30	13.90	0.524	0.547
e	5.45 BSC		0.215 BSC	
L	13.70	14.70	0.539	0.579
L1	1.00	1.60	0.039	0.063
R	2.00	3.00	0.079	0.118

Notes

- Dimensioning and tolerancing per ASME Y14.5M-1994
- Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outer extremes of the plastic body
- Outline conforms to JEDEC® outline to TO-274AA

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